ALPHA & OMEGA SEMICONDUCTOR

AON6718L
30V N-Channel MOSFET
SRFET™

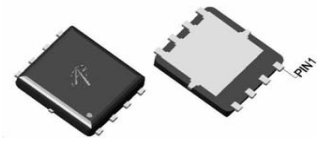
General Description

SRFET™ AON6718L uses advanced trench technology with a monolithically integrated Schottky diode to provide excellent $R_{DS(ON)}$,and low gate charge. This device is ideally suited for use as a low side switch in CPU core power conversion.

Features

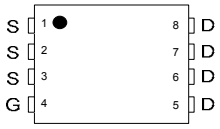
V_{DS} (V) = 30V
I_D = 80A (V_{GS} = 10V)
$R_{DS(ON)}$ < 3.7mΩ (V_{GS} = 10V)
$R_{DS(ON)}$ < 5mΩ (V_{GS} = 4.5V)

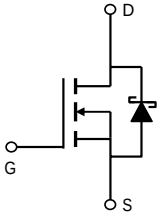
100% UIS Tested
100% Rg Tested



DFN5X6

Top View





SRFET™
Soft **R**ecovery MOS**FET**:
Integrated Schottky Diode

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	±20	V
Continuous Drain Current [G]	T_C=25°C	I_D	80	A
	T_C=100°C		63	
Pulsed Drain Current [C]		I_{DM}	210	
Continuous Drain Current	T_A=25°C	I_{DSM}	18	A
	T_A=70°C		15	
Avalanche Current [C]		I_{AR}	40	A
Repetitive avalanche energy L=0.1mH [C]		E_{AR}	80	mJ
Power Dissipation [B]	T_C=25°C	P_D	83	W
	T_C=100°C		33	
Power Dissipation [A]	T_A=25°C	P_{DSM}	2.1	W
	T_A=70°C		1.3	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	14.2	17	°C/W
Maximum Junction-to-Ambient [A D]	Steady-State		42	60	°C/W
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	1.2	1.5	°C/W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=250µA, V_{GS}=0V	30			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=30V, V_{GS}=0V		0.025	0.1	mA
		T_J=125°C			20	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}= ±20V			0.1	µA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=250µA	1.3	1.8	2.2	V
$I_{D(ON)}$	On state drain current	V_{GS}=10V, V_{DS}=5V	160			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=10V, I_D=20A		3.1	3.7	mΩ
		T_J=125°C		4.3	5.2	
		V_{GS}=4.5V, I_D=20A		4.1	5	mΩ
g_{FS}	Forward Transconductance	V_{DS}=5V, I_D=20A		87		S
V_{SD}	Diode Forward Voltage	I_S=1A,V_{GS}=0V		0.4	0.7	V
I_S	Maximum Body-Diode Continuous Current[G]				40	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=15V, f=1MHz	2975	3719	4463	pF
C_{oss}	Output Capacitance		485	693	900	pF
C_{rss}	Reverse Transfer Capacitance		204	340	476	pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz	0.28	0.56	0.84	Ω
SWITCHING PARAMETERS						
Q_g(10V)	Total Gate Charge	V_{GS}=10V, V_{DS}=15V, I_D=20A	48	60	72	nC
Q_g(4.5V)	Total Gate Charge		20	25	30	nC
Q_{gs}	Gate Source Charge		12	15	18	nC
Q_{gd}	Gate Drain Charge		6	10	14	nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=10V, V_{DS}=15V, R_L=0.75Ω, R_{GEN}=3Ω		9.2		ns
t_r	Turn-On Rise Time			10.7		ns
$t_{D(off)}$	Turn-Off DelayTime			40		ns
t_f	Turn-Off Fall Time			12.5		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=20A, dI/dt=500A/µs	10	13	16	ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=20A, dI/dt=500A/µs	21	26.5	32	nC

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The Power dissipation P_{DSM} is based on $R_{\theta JA}$ and the maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(MAX)}$=150°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$=150°C. Ratings are based on low frequency and duty cycles to keep initial T_J =25°C.

D. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$=150°C. The SOA curve provides a single pulse rating.

G. The maximum current rating is limited by bond-wires.

H. These tests are performed with the device mounted on 1 in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C.

Rev2: Oct-09

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

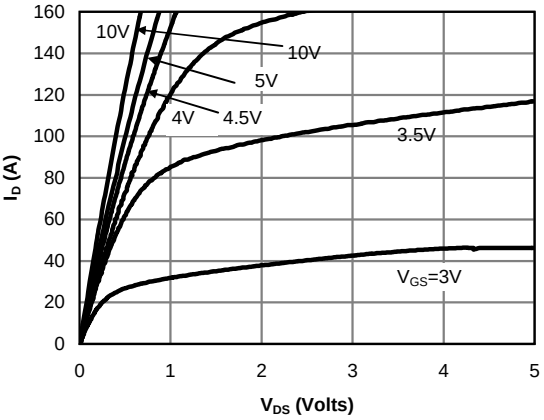


Fig 1: On-Region Characteristics (Note E)

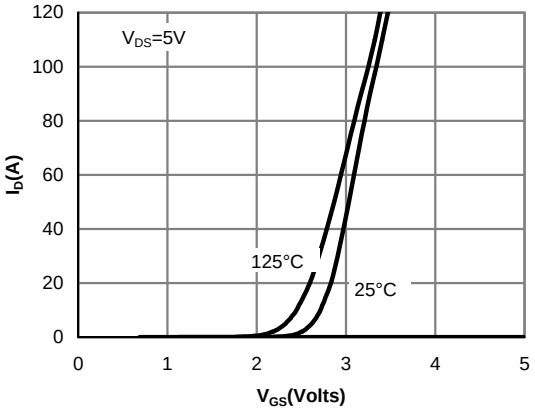


Figure 2: Transfer Characteristics (Note E)

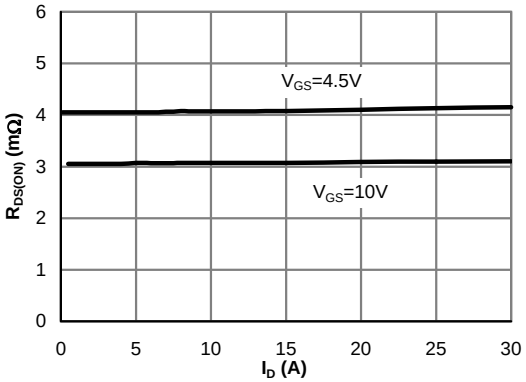


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

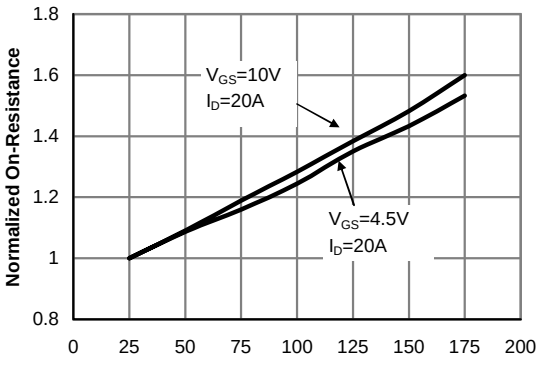


Figure 4: On-Resistance vs. Junction Temperature (Note E)

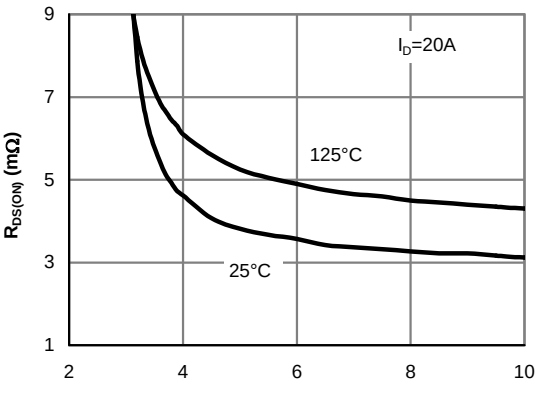


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

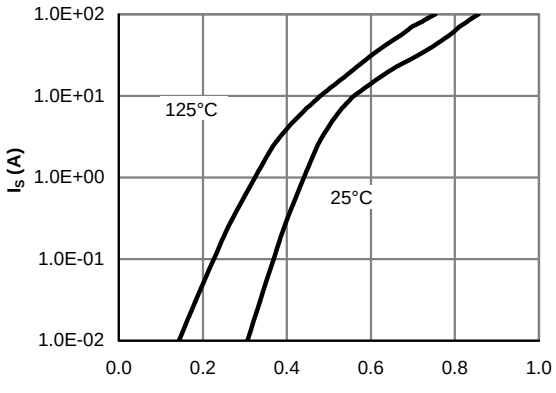


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

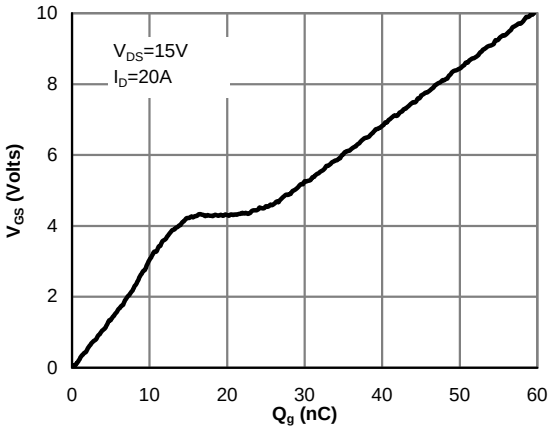


Figure 7: Gate-Charge Characteristics

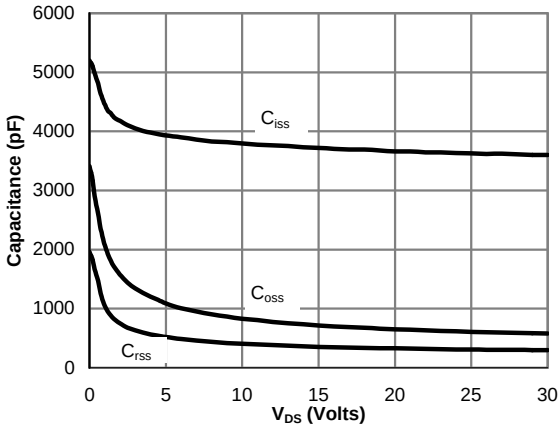


Figure 8: Capacitance Characteristics

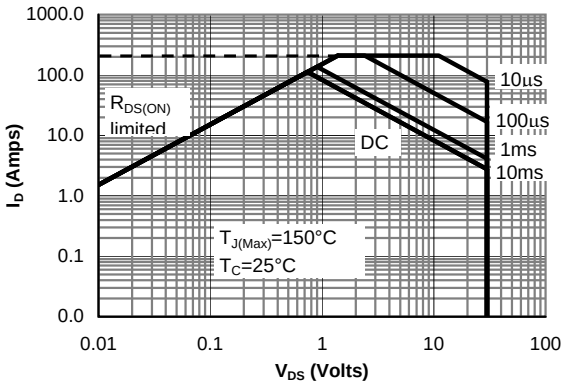


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

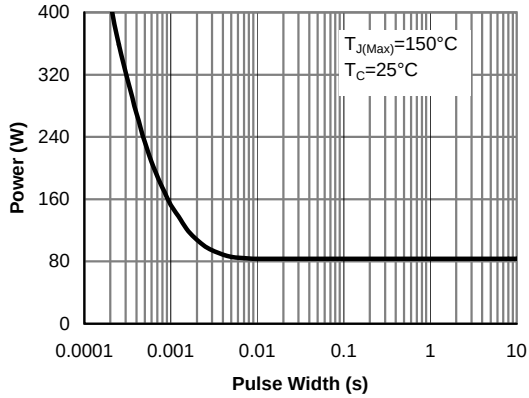


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

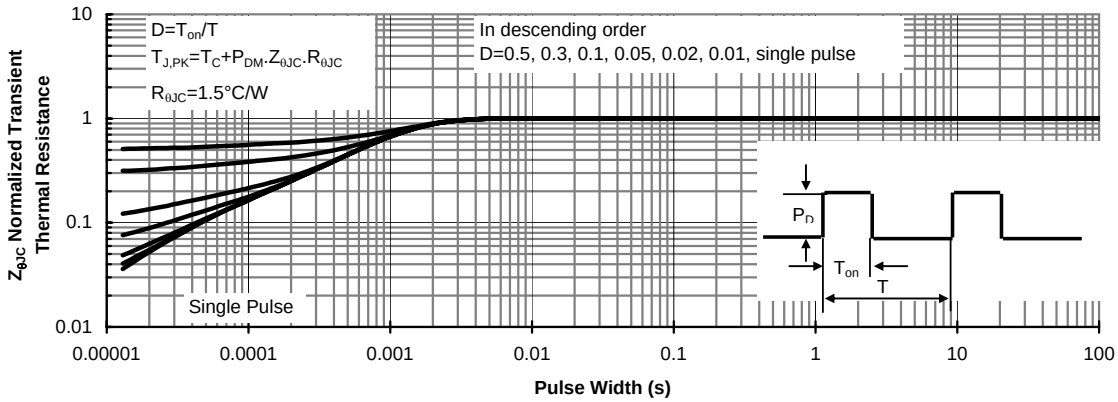


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

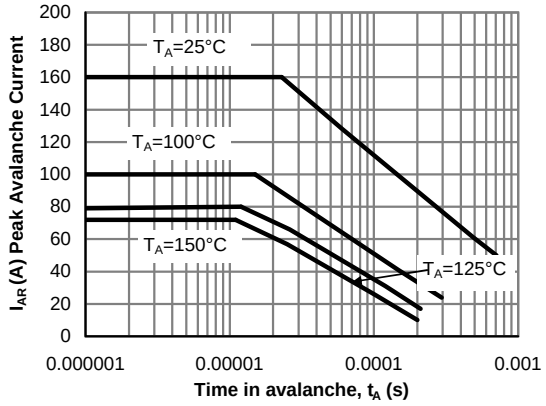


Figure 12: Single Pulse Avalanche capability (Note C)

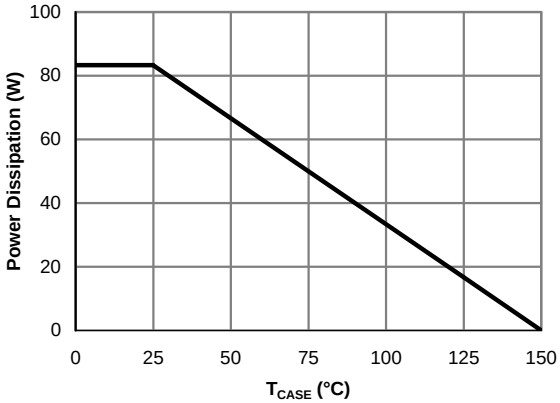


Figure 13: Power De-rating (Note F)

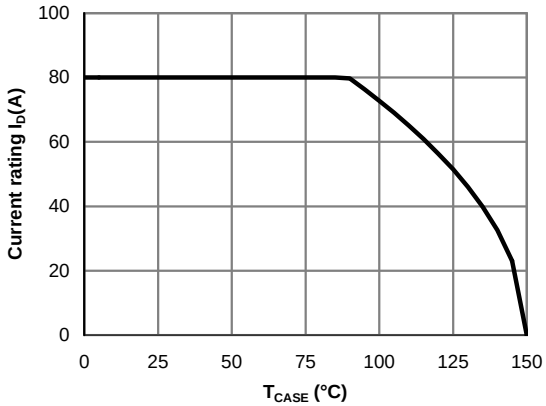


Figure 14: Current De-rating (Note F)

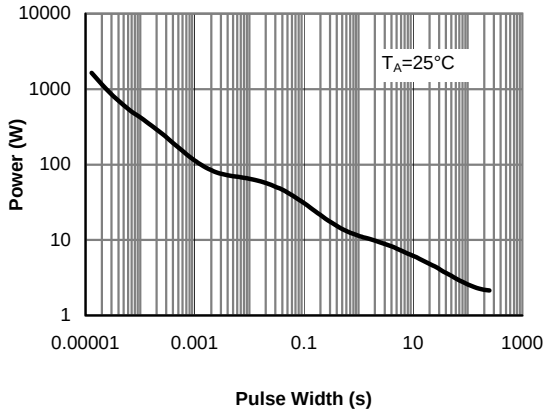


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

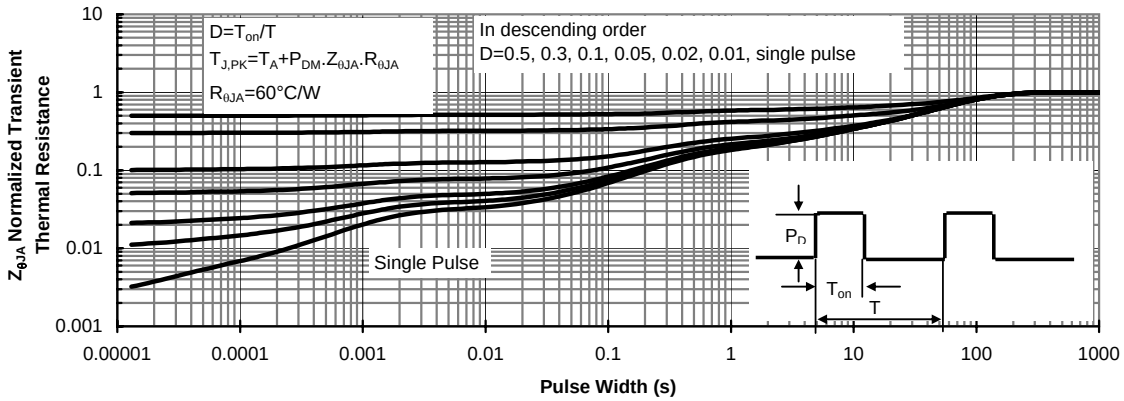


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

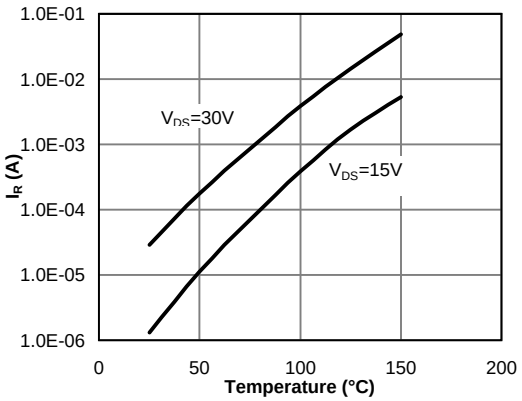


Figure 17: Diode Reverse Leakage Current vs. Junction Temperature

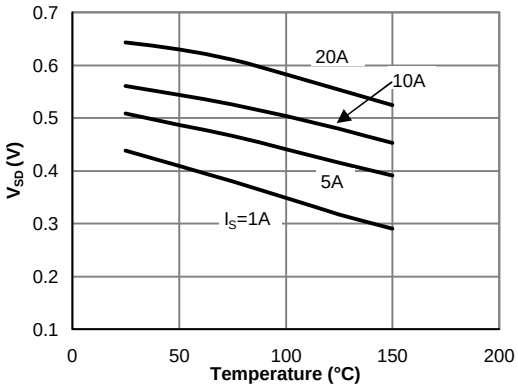


Figure 18: Diode Forward voltage vs. Junction Temperature

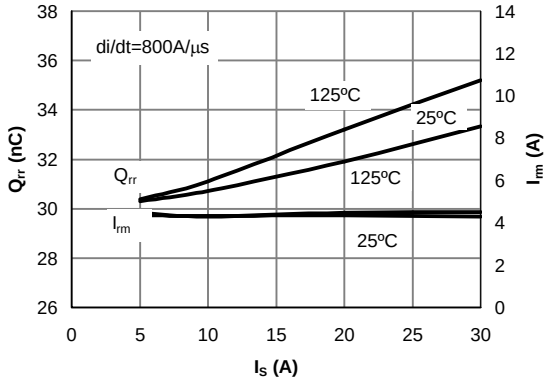


Figure 19: Diode Reverse Recovery Charge and Peak Current vs. Conduction Current

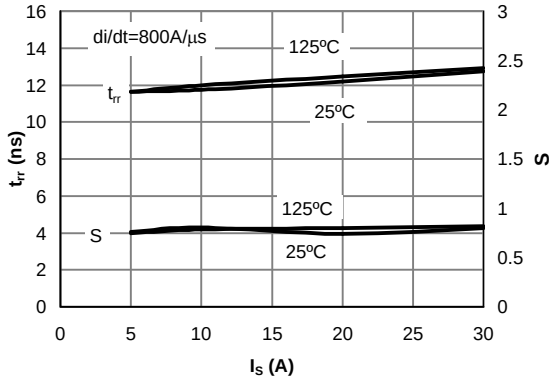


Figure 20: Diode Reverse Recovery Time and Softness Factor vs. Conduction Current

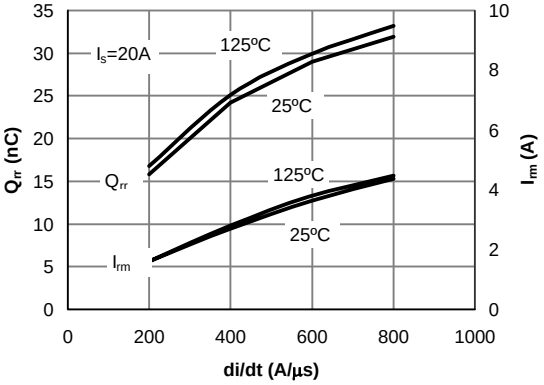


Figure 21: Diode Reverse Recovery Charge and Peak Current vs. di/dt

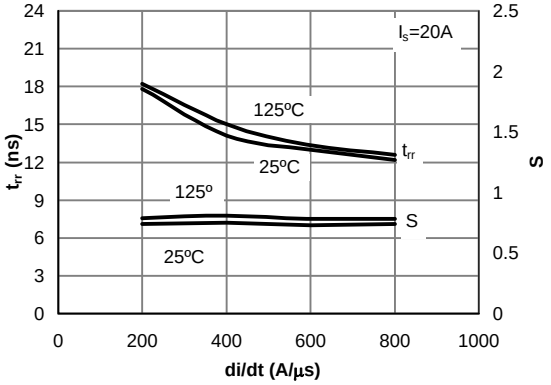
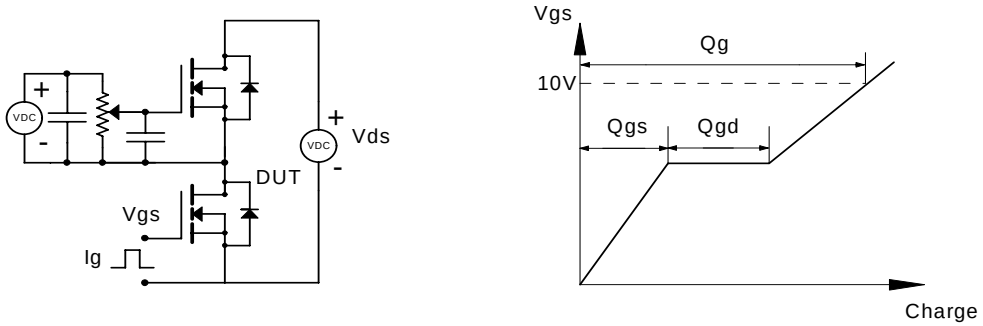
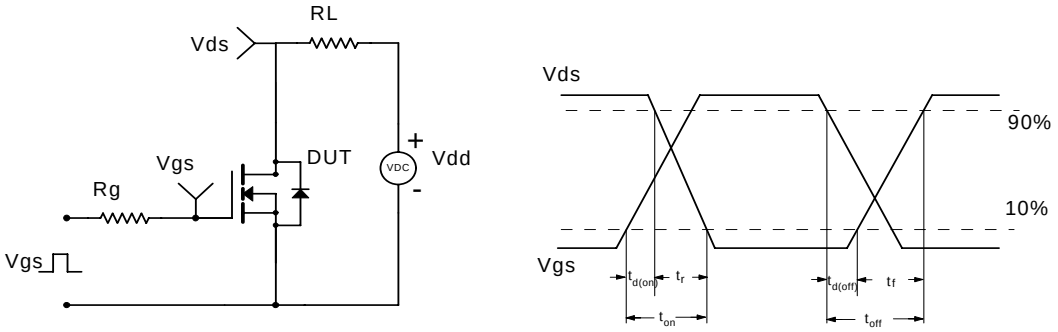


Figure 22: Diode Reverse Recovery Time and Softness Factor vs. di/dt

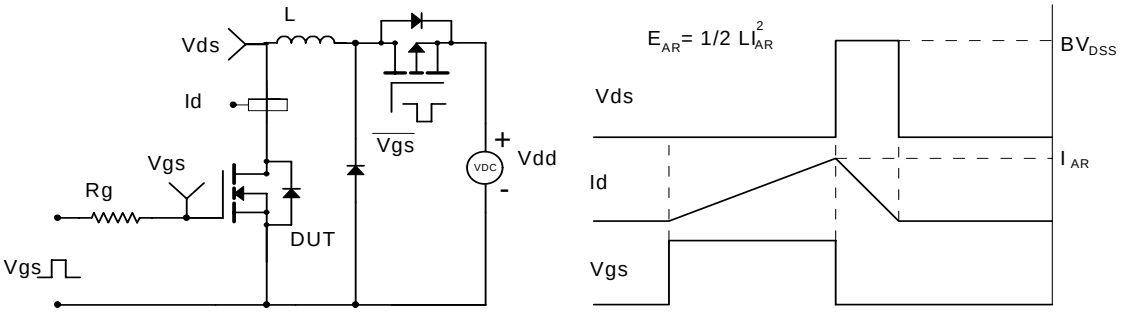
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms